

JTAG Test Systems



ASSET and Agilent Technologies announce two JTAG test systems to reduce costs for electronic equipment manufacturers by moving tests developed in the design department to a high-volume manufacturing environment, eliminating the need to re-develop tests in manufacturing. The solutions merge the capabilities of an ASSET ScanWorks Manufacturing Station and the Agilent 3070 ICT system. The final configuration of the solution is determined by a number of factors, including the volume of test, the financial requirements of the user organization and the current configuration of the user's 3070 system.

ASSET InterTech, Inc.

Source URL (retrieved on 03/06/2015 - 4:09am):

http://www.wirelessdesignmag.com/product-releases/2004/08/jtag-test-systems?qt-digital_editions=0